

Vishwani D. Agrawal is the James J. Danaher Professor of Electrical and Computer Engineering at Auburn University, Alabama. He has over forty years of industry and university experience, working at Bell Labs, Murray Hill, NJ; Rutgers University, New Brunswick, NJ; TRW, Redondo Beach, CA; IIT, Delhi, India; EG&G, Albuquerque, NM; and ATI, Champaign, IL. His areas of expertise include VLSI testing, low-power design, and microwave antennas.

He obtained his BE degree from the University of Roorkee (renamed *Indian Institute of Technology*), Roorkee, India, in 1964; ME degree from the Indian Institute of Science, Bangalore, India, in 1966; and PhD degree in electrical engineering from the University of Illinois, Urbana-Champaign, in 1971.

He has published over 300 papers, has coauthored five books and holds thirteen United States patents. His textbook, *Essentials of Electronic Testing for Digital, Memory and Mixed-Signal VLSI Circuits* (Kluwer Academic Publishers), co-authored with M. L. Bushnell, was published in 2000. He is the founder and Editor-in-Chief (1990-) of the *Journal of Electronic Testing: Theory and Applications*, and a past Editor-in-Chief (1985-87) of the *IEEE Design & Test of Computers* magazine. During 2003-08, he served on the Editorial Board of the IEEE Transactions on VLSI Systems. He is the founder and Consulting Editor of the *Frontiers in Electronic Testing* book series of Springer. He is a co-founder of the *International Conference on VLSI Design*, and the *International Workshops on VLSI Design and Test*, held annually in India. He has served on numerous conference committees and is a frequently invited speaker. He was the invited **Plenary Speaker** at the *1998 International Test Conference*, Washington, D.C., and the **Keynote Speaker** at the *Ninth Asian Test Symposium*, held in Taiwan in 2000. During 1989 and 1990, he served on the Board of Governors of the IEEE Computer Society, and in 1994, chaired the Fellow Selection Committee of that society.

He has received **eight Best Paper Awards** and **two Honorable Mention Paper Awards**. In 2006, he received the *Lifetime Achievement Award* of the VLSI Society of India, *in recognition of his contributions to the area of VLSI Test and for founding and steering the International Conference on VLSI Design in India*. In 1998, he received the **Harry H. Goode Memorial Award** of the IEEE Computer Society, *for innovative contributions to the field of electronic testing*, and in 1993, received the **Distinguished Alumnus Award** of the University of Illinois at Urbana-Champaign, *in recognition of his outstanding contributions in design and test of VLSI systems*. Dr. Agrawal is a **Fellow of IETE-India** (elected in 1983), a **Fellow of the IEEE** (elected in 1986), and a **Fellow of the ACM** (elected in 2003). He has served on the Advisory Boards of the ECE Departments of the University of Illinois, New Jersey Institute of Technology, and the City College of the City University of New York. See his website – <http://www.eng.auburn.edu/~vagrawal>. (Updated 11/18/11)